

DC FAN LIFE EXPERIMENT REPORT

Available for these models with lower speed and same physical	BFB1024H	BFB1024M	BFB1012HH-TP48					
structure.	BFB1024HH	BFB1012L						
All model may be followed byRxx orFxx series suffixes.	BFB1012H	BFB1024M						
This test report applies to BFB 97x94x33 mm series as the right table	BFB1012M	BFB1012MX01						
Representative Test P/N : BFB1012HH								
		On/Off Cycles: Every 500 hours						
Equipment: 1.Oven: E24-T0170			On/Off Cycles:	: Every 500 h	ours			
Equipment: 1.Oven: E24-T0170 \bigcirc L ₁₀ Expectancy: 50,000 hours minimu	ım @ fan ra	ated voltage a	2	2				
		8	2	2	C			

the total test time (t) for verifying the above life estimation by the equations,

 $t = 1.036 \times MTTF \times [(B_{r;c}) \div n]^{0.91} \div A_F, \text{ and } A_F = 2^{(Ts - Tu)/10}$

where, $(B_{r,c})$ is Poisson distribution factor with the failure number of r equal to 0 and

the decimal confidence level of c equal to 0.90(90%).

Stress/Elevated Temperature Ts (℃)	Unstress Temperature Tu (°C)	Acceleration Factor A _F	Quantity of Test Devices n (pcs)	Poisson Distribution Factor B _{r;c}	Required test time with zero failure t (hours)	Actual test time with zero failure t (hours)	Verified MTTF 40 °C (hours)	Verified L ₁₀ 40 °C (hours)
70	40	8.00	19	2.303	6,643	12,042.0	634,464	90,638

Test Progress:

Date for Test I	Beginning		for Test ion (at least)	rrent Test Sta	atus	Current Total Test Time (hours)		
1998/8/17 1:	:00 PM	1999/5/2	21 7:55 AM	✓ Termination	12042.0			
Herewith , we could if the actual test times the second se	ne exceed the	required, it co	omes out that those	fans' L ₁₀	Temperature for MTTF Estimation (℃)	Acceleration Factor A _F	Estimated MTTF (hours)	Estimated L ₁₀ (hours)
expectancy and MTTF are greater than the warrant. (MTTF : means Mean Time To Failures, it should be used in a non-repairable system setting. Now we show the MTTF in our life report, that's because we will not repair the failed fans during life experiment. MTBF : means Mean Time Between failures, it should be used in a repairable system setting.					25	22.63	1,794,536	256,362
					30	16.00	1,268,928	181,275
					40	8.00	634,464	90,638
					50	4.00	317,232	45,319
 Fan permission criteria for the measurement after test : 1. Speed can not drop of ≥ 15% below the original measured rpm. 2. Current cannot increase > 15% of original measure current. 3. Noise cannot >3dB over the original measure noise. 					60	2.00	158,616	22,659
					70	1.00	79,308	11,330
					Test Result		✓	Accept Reject
OF File No 1	Time-out fo test or othe	or function rs (hours)	Issued	Date	Report	ted By	Approved By	
A113L	2840	.00	2000/4/28	3:00PM	Bomice Chang Poter Sir			



DC FAN FUNCTION TEST RECORD FOR LIFE EXPERIMENT

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Available fo	r these models w	ith lower speed a	nd same nhysic	al structure	BFB1024H	BFB1024M	BFB1012HH-TP48			
Available for these models with lower speed and same physic All model may be followed byRxx orFxx series suffixes.		ai su deture.	BFB1024HH	BFB1012L						
	ort applies to BI	•		ght table	BFB1012H	BFB1024M				
					BFB1012M	BFB1012MX01				
-	l Test Time hrs)	Date fo Begin			or Test ination	Sample Size (pcs):	Failure (pcs):			
6,	,643	1998/8/17	1:00 PM	1999/5/22	1 7:55 AM	19	0	1204	2.0	
Represen	tative Test P	/N: BFB10	12HH		Current Test Status		In process	In process (exceed requested)		
Equipme	nt: 1.Oven:	E24-T0170					On/Off Cycl	es: Every 500	hours	
			Test Data	Between In	itial Test an	d Final Tes	t			
Sample No.	Initial Test Current Spec. (mA)	Final Test Current Spec. (mA)	Deviation (%)	Initial Test Speed Spec. (RPM)	Final Test Speed Spec. (RPM)	Deviation (%)	Initial Test Noise Spec. (dB A)	Final Test Noise Spec. (dB A)	Deviation	
110.	(IIIA) 1.65 Max.	(IIIA) 1.65 Max.	(70)	(RI W) 4000Ref.	(IXI IVI) 4000Ref.	(70)	(uB A) 58.0 Max	(ub A) 61.0 Max	3 dBMax.	
1	1.05 Max.	1.05 Max.	0.0	4000Kel. 4011	4000Ref. 4084	1.8	56.0	55.7	-0.3	
2	1.02	1.02	-1.0	4011 4257	4084	0.8	57.4	56.9	-0.5	
2		1.01	-1.9	4237		1.6	56.8	56.3	-0.5	
4	1.03	1.01	-1.9	-	4221	1.4	56.3	57.2	0.9	
- 5	1.04	1.02	-1.0	4134 4135	4191 4196	1.5	56.9	56.2	-0.7	
6	1.01	1.00	-0.9	4043	4043	0.0	56.4	55.6	-0.7	
7			-0.9			1.3	56.1	56.1	0.0	
8	1.03	1.01	-1.9	4094	4146	0.1	56.8	56.9	0.0	
9	1.07	1.05 1.07	-0.9	4196 4102	4201 4159	1.4	55.6	55.1	-0.5	
9 10			-0.9			0.5	56.3	54.8	-0.5	
10	1.03	1.01 1.03	-1.9	4106	4128	1.4	57.3	56.3	-1.0	
11	1.04		-2.0	4233	4293	1.4	56.5	55.1	-1.0	
12	1.02	1.00	-2.0	4112	4172	2.1	56.4	55.5	-1.4	
13	1.13 1.03	1.13 1.01	-1.9	4058 4128	4143 4169	1.0	56.2	56.2	0.0	
14		1.01	-0.9	4128	4169	1.0	56.0	55.5	-0.5	
15	1.10		-0.9	-		1.7	56.5	56.2	-0.3	
10	1.02	1.01	-1.0	4123	4181	2.3	56.1	55.6	-0.5	
17	1.01 1.02	1.00 1.02	0.0	4043 4147	4134 4242	2.3	56.8	56.6	-0.2	
10		1.02	-0.9	4147	4242	1.0	56.8	56.1	-0.2	
17	1.15	1.14	-0.9	4102	4145	1.0	50.0	50.1	-0.7	
X-Bar	1.0	1.0		1115 2	4160 5		56 10	55.00		
	1.0	1.0	-	4115.3	4169.5	-	56.48	55.99	-	
σ	0.041	0.043	-	66.707	65.291	-	0.459	0.654	-	
QEI	QE File No.		Time-out for function test or others (hrs)		Issued Date		ted By	Approved By		
A	A113L 284		.00	2000/4/2	8 3:00PM	Bomia	Chang	Poter	Sur	